

ON Semiconductor®

FDS6673BZ P-Channel PowerTrench[®] MOSFET -30V, -14.5A, 7.8mΩ

General Description

This P-Channel MOSFET is produced using ON Semiconductor's advanced Power Trench process that has been especially tailored to minimize the on-state resistance.

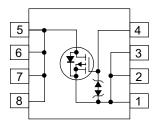
This device is well suited for Power Management and load switching applications common in Notebook Computers and Portable Battery Packs.



Features

- Max $r_{DS(on)} = 7.8 m\Omega$, $V_{GS} = -10V$, $I_D = -14.5A$
- Max $r_{DS(on)} = 12m\Omega$, $V_{GS} = -4.5V$, $I_D = -12A$
- Extended V_{GS} range (-25V) for battery applications
- HBM ESD protection level of 6.5kV typical (note 3)
- High performance trench technology for extremely low r_{DS(on)}
- High power and current handling capability
- RoHS compliant





MOSFET Maximum Ratings $T_A = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DS}	Drain to Source Voltage		-30	V
V _{GS}	Gate to Source Voltage		±25	V
I _D	Drain Current -Continuous (I	Note1a)	-14.5	A
	-Pulsed		-75	A
P _D	Power Dissipation for Single Operation (Note1a)	2.5	
	(Note1b)	1.2	W
	(Note1c)	1.0	
T _J , T _{STG}	Operating and Storage Temperature		-55 to 150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	50	°C/W
$R_{ ext{ heta}JC}$	Thermal Resistance, Junction to Case (Note 1)	25	°C/W

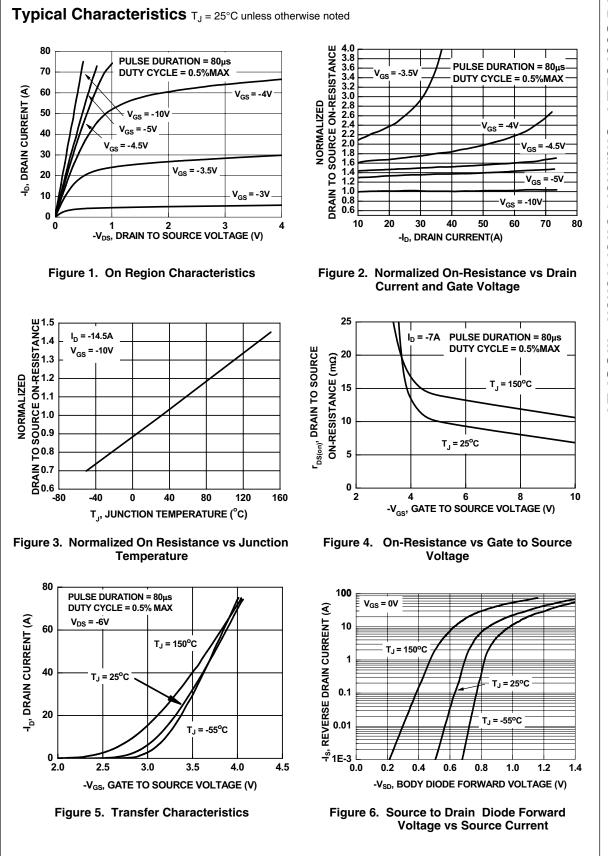
Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape Width	Quantity
FDS6673BZ	FDS6673BZ	13"	12mm	2500 units

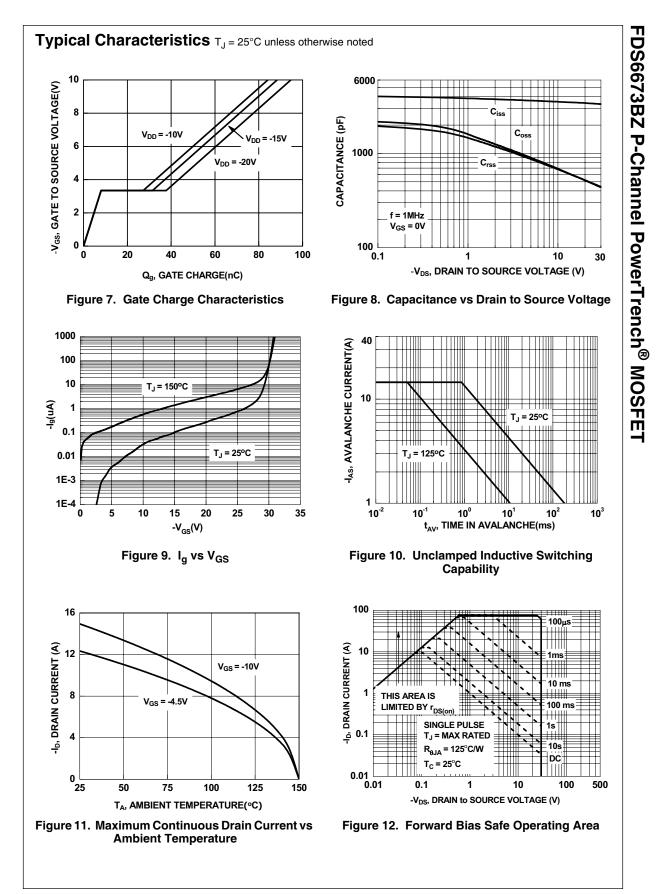
B _{VDSS} ΔB _{VDSS} ΔT _J I _{DSS} I _{GSS} On Chara	cteristics Drain to Source Breakdown Voltage Breakdown Voltage Temperature Coefficient Zero Gate Voltage Drain Current Gate to Source Leakage Current cteristics (Note 2)	$\begin{split} I_{D} &= -250 \mu A, \ V_{GS} = 0 V \\ I_{D} &= -250 \mu A, \ referenced \ to \\ 25^{\circ}C \\ V_{DS} &= -24 V, \ V_{GS} = 0 V \\ V_{GS} &= \pm 25 V, \ V_{DS} = 0 V \end{split}$	-30			
ΔB _{VDSS} ΔT _J loss loss On Chara V _{GS(th)} ΔV _{GS(th)}	Breakdown Voltage Temperature Coefficient Zero Gate Voltage Drain Current Gate to Source Leakage Current Cteristics (Note 2)	$I_D = -250\mu$ A, referenced to 25°C $V_{DS} = -24V, V_{GS} = 0V$	-30			
$\frac{\Delta B_{VDSS}}{\Delta T_J}$ $\frac{I_{DSS}}{I_{GSS}}$ On Charace $\frac{V_{GS(th)}}{\Delta V_{GS(th)}}$	Coefficient Zero Gate Voltage Drain Current Gate to Source Leakage Current Cteristics (Note 2)	$I_D = -250\mu$ A, referenced to 25°C $V_{DS} = -24V, V_{GS} = 0V$				V
I _{DSS} I _{GSS} On Chara V _{GS(th)} ΔV _{GS(th)}	Gate to Source Leakage Current cteristics (Note 2)			-20		mV/°C
I _{GSS} On Charac V _{GS(th)} ΔV _{GS(th)}	cteristics (Note 2)		-		-1	μA
$V_{GS(th)}$ $\Delta V_{GS(th)}$		1			±10	μA
$V_{GS(th)}$ $\Delta V_{GS(th)}$						
$\Delta V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = -250 \mu A$	-1	-1.9	-3	V
	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = -250 \mu A$, referenced to $25^{\circ}C$		8.1		mV/°C
		V _{GS} = -10V , I _D = -14.5A		6.5	7.8	
r	Drain to Source On Besistance	$V_{GS} = -4.5V, I_D = -12A$		9.6	12	
r _{DS(on)}	Drain to Source On Resistance	$V_{GS} = -10V, I_D = -14.5A$ $T_J = 125^{\circ}C$		9.7	12	- mΩ
9 _{FS}	Forward Transconductance	V _{DS} = -5V, I _D = -14.5A		60		S
	Characteristics	1				
C _{iss}	Input Capacitance			3500	4700	pF
C _{oss}	Output Capacitance	$V_{DS} = -15V, V_{GS} = 0V,$		600	800	pF
C _{rss}	Reverse Transfer Capacitance	f = 1.0MHz		600	900	pF
	Characteristics (Note 2)					
e milening						
t _{d(on)}	Turn-On Delay Time			14	26	ns
	Turn-On Delay Time Rise Time	V _{DD} = -15V, I _D = -1A		14 16	26 29	ns ns
t _r	Rise Time	V _{DD} = -15V, I _D = -1A -V _{GS} = -10V, R _{GS} = 6Ω			-	
t _r t _{d(off)}	,			16	29	ns
t _r t _{d(off)} t _f	Rise Time Turn-Off Delay Time			16 225	29 36	ns ns
t _r t _{d(off)} t _f Q _g	Rise Time Turn-Off Delay Time Fall Time	$V_{GS} = -10V, R_{GS} = 6\Omega$ $V_{DS} = -15V, V_{GS} = -10V,$ $I_{D} = -14.5A$		16 225 105	29 36 167	ns ns ns
t _r t _{d(off)} t _f Q _g Q _g	Rise Time Turn-Off Delay Time Fall Time Total Gate Charge	$V_{GS} = -10V, R_{GS} = 6\Omega$ $V_{DS} = -15V, V_{GS} = -10V,$ $I_D = -14.5A$ $V_{DS} = -15V, V_{GS} = -5V,$		16 225 105 88	29 36 167 124	ns ns ns nC
t _r t _{d(off)} t _f Q _g Q _g Q _{gs}	Rise Time Turn-Off Delay Time Fall Time Total Gate Charge Total Gate Charge	$V_{GS} = -10V, R_{GS} = 6\Omega$ $V_{DS} = -15V, V_{GS} = -10V,$ $I_{D} = -14.5A$		16 225 105 88 46	29 36 167 124	ns ns nS nC nC
t _r t _{d(off)} t _f Q _g Q _g Q _{gs} Q _{gd}	Rise Time Turn-Off Delay Time Fall Time Total Gate Charge Total Gate Charge Gate to Source Gate Charge Gate to Drain Charge	$V_{GS} = -10V, R_{GS} = 6\Omega$ $V_{DS} = -15V, V_{GS} = -10V,$ $I_D = -14.5A$ $V_{DS} = -15V, V_{GS} = -5V,$		16 225 105 88 46 8	29 36 167 124	ns ns nC nC nC
t _r t _{d(off)} C _g C _g C _{gs} C _{gg} C _{gg} Drain-Sou	Rise Time Turn-Off Delay Time Fall Time Total Gate Charge Total Gate Charge Gate to Source Gate Charge Gate to Drain Charge urce Diode Characteristics	$V_{GS} = -10V, R_{GS} = 6\Omega$ $V_{DS} = -15V, V_{GS} = -10V,$ $I_D = -14.5A$ $V_{DS} = -15V, V_{GS} = -5V,$ $I_D = -14.5A$		16 225 105 88 46 8	29 36 167 124	ns ns nC nC nC
t _r t _{d(off)} Q _g Q _g Q _{gs} Q _{gd} Drain-Sou V _{SD}	Rise Time Turn-Off Delay Time Fall Time Total Gate Charge Total Gate Charge Gate to Source Gate Charge Gate to Drain Charge	$V_{GS} = -10V, R_{GS} = 6\Omega$ $V_{DS} = -15V, V_{GS} = -10V,$ $I_D = -14.5A$ $V_{DS} = -15V, V_{GS} = -5V,$ $I_D = -14.5A$		16 225 105 88 46 8 23.5	29 36 167 124 65	ns ns nC nC nC nC
$\frac{t_{d(on)}}{t_r}$ $\frac{t_{d(off)}}{t_f}$	Rise Time Turn-Off Delay Time Fall Time	$V_{GS} = -10V, R_{GS} = 6\Omega$		16 225 105	29 36 167	
t _r t _{d(off)} t _f Q _g Q _g Q _{gs} Q _{gd}	Rise Time Turn-Off Delay Time Fall Time Total Gate Charge Gate to Source Gate Charge Gate to Drain Charge Ince Diode Characteristics Source to Drain Diode Forward Voltage	$V_{GS} = -10V, R_{GS} = 6\Omega$ $V_{DS} = -15V, V_{GS} = -10V,$ $I_{D} = -14.5A$ $V_{DS} = -15V, V_{GS} = -5V,$ $I_{D} = -14.5A$ $V_{GS} = 0V, I_{S} = -2.1A$		16 225 105 88 46 8 23.5	29 36 167 124 65 -1.2	ns ns nC nC nC v

Scale 1 : 1 on letter size paper

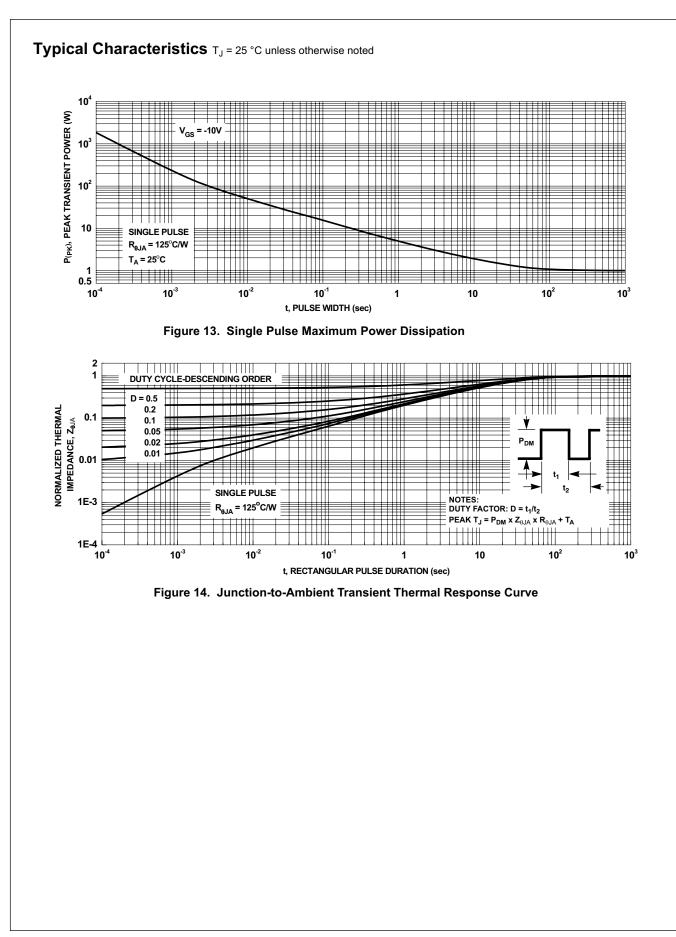
Pulse Test: Pulse Width < 300μs, Duty Cycle < 2.0%.
 The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.



FDS6673BZ P-Channel PowerTrench[®] MOSFET



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